



Model: SAMSUNG MZ7LM1T9

S/N: S2TVNX0J501437

Disk Erasure Report

Page 1 - Erasure Status



Organisation Performing The Disk Erasure

Business Name: **GridJet**

Business Address:

Contact Name: **GDW-LDS-6**

Contact Phone:

Customer Details

Name: **Gridjet**

Address:

Contact Name:

Contact Phone:

Disk Information

Make/Model: **SAMSUNG MZ7LM1T9**

Serial: **S2TVNX0J501437**

Size(Apparent): **1920 GB, 1920383410176 bytes**

Bus: **ATA-SSD**

Size(Real): **1920 GB, 1920383410176 bytes**

Disk Erasure Details

Start time: **2026/01/21 16:00:12**

End time: **2026/01/21 22:39:03**

Duration: **06:38:51**

Status: **ERASED**

Method: **PRNG Stream**

PRNG algorithm: **XORshiro256**

Final Pass(Zeros/Ones/None): **Zeros**

Verify Pass(Last/All/None): **Verify Last**

*Bytes Erased: **1920383410176, (100.00%)**

Rounds(completed/requested): **1/1**

HPA/DCO: **No hidden sectors**

HPA/DCO Size: **No hidden sectors**

Errors(pass/sync/verify): **0/0/0**

Throughput: **240 MB/sec**

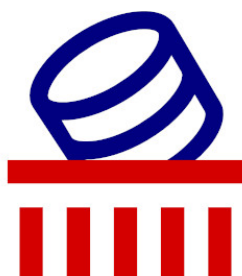
Information:

* bytes erased: The amount of drive that's been erased at least once

Technician/Operator ID

Signature:

Name/ID: **Auto Wipe**



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smartctl 7.2 2020-12-30 r5155 [x86_64-linux-5.14.0-503.23.1.el9_5.x86_64] (local build)
copyright (c) 2002-20, bruce allen, christian franke, www.smartmontools.org

=== start of information section ===

model family: Samsung based SSDs
device model: SAMSUNG MZ7LM1T9HMP-00005
serial number: S2TVNX0J501437
lu wwn device id: 5 002538 c405e8704
firmware version: GXT5204Q
user capacity: 1,920,383,410,176 bytes [1.92 TB]
sector size: 512 bytes logical/physical
rotation rate: Solid State Device
form factor: 2.5 inches
trim command: Available, deterministic, zeroed
device is: In smartctl database [for details use: -P show]
ata version is: ACS-2, ATA8-ACS T13/1699-D revision 4c
sata version is: SATA 3.1, 6.0 Gb/s (current: 6.0 Gb/s)
local time is: Wed Jan 21 22:39:05 2026 GMT
smart support is: Available - device has SMART capability.
smart support is: Enabled

=== start of read smart data section ===

smart overall-health self-assessment test result: PASSED

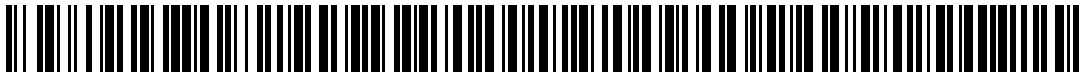
general smart values:

offline data collection status: (0x02)Offline data collection activity
was completed without error.
auto offline data collection: Disabled.
self-test execution status: (0)The previous self-test routine completed
without error or no self-test has ever
been run.
total time to complete offline
data collection: (6000) seconds.
offline data collection
capabilities: (0x53) SMART execute Offline immediate.
auto offline data collection on/off support.
suspend offline collection upon new
command.
no offline surface scan supported.
self-test supported.
no conveyance self-test supported.
selective self-test supported.
smart capabilities: (0x0003)Saves SMART data before entering
power-saving mode.
supports smart auto save timer.
error logging capability: (0x01)Error logging supported.
general purpose logging supported.
short self-test routine
recommended polling time: (2) minutes.
extended self-test routine
recommended polling time: (100) minutes.
sct capabilities: (0x003d)SCT Status supported.
sct error recovery control supported.
sct feature control supported.
sct data table supported.

smart attributes data structure revision number: 1

vendor specific smart attributes with thresholds:

id#	attribute_name	flag	value	worst	thresh	type	updated	when_failed	raw_value
5	reallocated_sector_ct	0x0033	096	096	010	pre-fail	always	-	220
9	power_on_hours	0x0032	087	087	000	old_age	always	-	64019
12	power_cycle_count	0x0032	099	099	000	old_age	always	-	25
177	wear_leveling_count	0x0013	093	093	005	pre-fail	always	-	491
179	used_rsvid_blk_cnt_tot	0x0013	096	096	010	pre-fail	always	-	220



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180	unused_rsvd_blk_cnt_tot	0x0013	096	096	010	pre-fail	always	-	6341
181	program_fail_cnt_total	0x0032	100	100	010	old_age	always	-	0
182	erase_fail_count_total	0x0032	100	100	010	old_age	always	-	0
183	runtime_bad_block	0x0013	096	096	010	pre-fail	always	-	220
184	end-to-end_error	0x0033	100	100	097	pre-fail	always	-	0
187	uncorrectable_error_cnt	0x0032	099	099	000	old_age	always	-	558
190	airflow_temperature_cel	0x0032	063	056	000	old_age	always	-	37
194	temperature_celsius	0x0022	063	056	000	old_age	always	-	37 (min/max 19/44)
195	ecc_error_rate	0x001a	199	199	000	old_age	always	-	558
197	current_pending_sector	0x0032	100	100	000	old_age	always	-	0
199	crc_error_count	0x003e	100	100	000	old_age	always	-	0
202	exception_mode_status	0x0033	100	100	010	pre-fail	always	-	0
235	por_recovery_count	0x0012	099	099	000	old_age	always	-	18
241	total_lbas_written	0x0032	099	099	000	old_age	always	-	1301345446973
242	total_lbas_read	0x0032	099	099	000	old_age	always	-	2169306436219
243	sata_downshift_ct	0x0032	100	100	000	old_age	always	-	0
244	thermal_throttle_st	0x0032	100	100	000	old_age	always	-	0
245	timed_workld_media_wear	0x0032	100	100	000	old_age	always	-	65535
246	timed_workld_rdw_ratio	0x0032	100	100	000	old_age	always	-	65535
247	timed_workld_timer	0x0032	100	100	000	old_age	always	-	65535
251	nand_writes	0x0032	100	100	000	old_age	always	-	2111944325120

smart error log version: 1

ata error count: 558 (device log contains only the most recent five errors)

cr = command register [hex]

fr = features register [hex]

sc = sector count register [hex]

sn = sector number register [hex]

cl = cylinder low register [hex]

ch = cylinder high register [hex]

dh = device/head register [hex]

dc = device command register [hex]

er = error register [hex]

st = status register [hex]

powered_up_time is measured from power on, and printed as

ddd+hh:mm:ss.sss where DD=days, hh=hours, mm=minutes,

ss=sec, and sss=millisec. it "wraps" after 49.710 days.

error 558 occurred at disk power-on lifetime: 62954 hours (2623 days + 2 hours)
when the command that caused the error occurred, the device was active or idle.

after command completion occurred, registers were:

er st sc sn cl ch dh

-- -- -- -- --

00 51 00 57 3d 59 40 error:

commands leading to the command that caused the error were:

cr fr sc sn cl ch dh dc powered_up_time command/feature_name

-- -- -- -- --

error 557 occurred at disk power-on lifetime: 62954 hours (2623 days + 2 hours)
when the command that caused the error occurred, the device was active or idle.

after command completion occurred, registers were:

er st sc sn cl ch dh

-- -- -- -- --

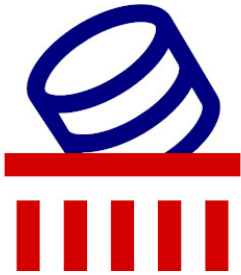
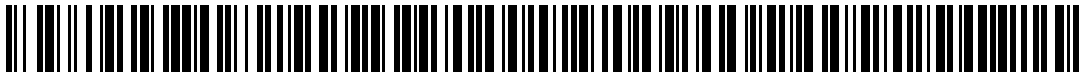
00 51 00 56 3d 59 40 error:

commands leading to the command that caused the error were:

cr fr sc sn cl ch dh dc powered_up_time command/feature_name

-- -- -- -- --

error 556 occurred at disk power-on lifetime: 62954 hours (2623 days + 2 hours)
when the command that caused the error occurred, the device was active or idle.



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after command completion occurred, registers were:

er st sc sn cl ch dh

-- -- -- -- --

00 51 00 55 3d 59 40 error:

commands leading to the command that caused the error were:

cr fr sc sn cl ch dh dc powered_up_time command/feature_name

-- -- -- -- --

error 555 occurred at disk power-on lifetime: 62954 hours (2623 days + 2 hours)
when the command that caused the error occurred, the device was active or idle.

after command completion occurred, registers were:

er st sc sn cl ch dh

-- -- -- -- --

00 51 00 54 3d 59 40 error:

commands leading to the command that caused the error were:

cr fr sc sn cl ch dh dc powered_up_time command/feature_name

-- -- -- -- --

error 554 occurred at disk power-on lifetime: 62954 hours (2623 days + 2 hours)
when the command that caused the error occurred, the device was active or idle.

after command completion occurred, registers were:

er st sc sn cl ch dh

-- -- -- -- --

00 51 00 53 3d 59 40 error:

commands leading to the command that caused the error were:

cr fr sc sn cl ch dh dc powered_up_time command/feature_name

-- -- -- -- --

smart self-test log structure revision number 1
no self-tests have been logged. [to run self-tests, use: smartctl -t]

smart selective self-test log data structure revision number 1

span	min_lba	max_lba	current_test_status
1	0	0	not_testing
2	0	0	not_testing
3	0	0	not_testing
4	0	0	not_testing
5	0	0	not_testing
255	0	65535	read_scanning was completed without error

selective self-test flags (0x0):
after scanning selected spans, do not read-scan remainder of disk.
if selective self-test is pending on power-up, resume after 0 minute delay.